


<b>Search Notes</b> 	<b>Application/Control No.</b> 10585604	<b>Applicant(s)/Patent Under Reexamination</b> DOBKIN ET AL.
	<b>Examiner</b> SHEELA C CHAWAN	<b>Art Unit</b> 2624

### SEARCHED

Class	Subclass	Date	Examiner
382	100, 115	6/6/09	SCC
726	22,23,25	6/6/09	SCC
705	4	6/6/09	SCC
340	5.26,426.25,5.64,5.72,825.69,628,690,428,518,521,511, 5.82	6/6/09	SCC
713	187,188,190	6/6/09	SCC
726	25, 22, 23, 24	6/6/09	SCC
706	14	6/6/09	SCC
324	178	"	"
307	10.2	"	"
380	262, 28	"	"
180	287	"	"
375	138	"	"
ABOVE SEARCH UP-DATE.		"	"
382	100, 115	6/6/09	SCC
726	22	6/6/09	SCC
706	14	6/6/09	SCC
340	5.82, 426.25	6/6/09	SCC
ABOVE SEARCH UP-DATE.		6/6/09	SCC

### SEARCH NOTES

Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE , SEE THE SEARCH HISTORY.	6/6/09	SCC
382/100., 115 . ccls. US-PATENT TEXT SEARCH ONLY.	"	"
726/22,23,25.ccls. US-PATENT TEXT SEARCH ONLY.	6/6/09	SCC
340/5.26,426.25,5.64,5.72,825.69,628,690,428,518,521,511, 5.82.ccls. US-PATENT TEXT SEARCH ONLY.	"	"
706/14.CCLS. US-PATENT TEXT SEARCH ONLY.	"	"
324/138. CCLS. US-PATENT TEXT SEARCH ONLY	6/6/09	"
SEARCH INVENTOR NAME.	"	"
DISCUSS WITH SAMIR AHMED SPE ART UNIT 2624.	"	"

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**SEARCH NOTES**

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
INTERFERENCE SEARCH.	"	"
ABOVE SEARCH UP-DATE	"	"
SEARCH IEEE OR INSPEC DATA BASE.	"	"
ABOVE SEARCH UP-DATE	"	"

**INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100, 115	6/6/09	SCC
726	22	6/6/09	SCC
706	14	6/6/09	SCC
340	426.25	6/6/09	SCC

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